

Search Notes

Application/Control No.

10/822,177

Examiner

VanThu Nguyen

Applicant(s)/Patent under
Reexamination

NOGUCHI ET AL.

Art Unit

2824

SEARCHED

Class	Subclass	Date	Examiner
365	185.09 o 185.17 x 185.33 x	10/26/2005	VTN
	185.03 x		
	185.11 x		
714	764 x		
	778 x		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search (see print out history)	10/26/2005	VTN